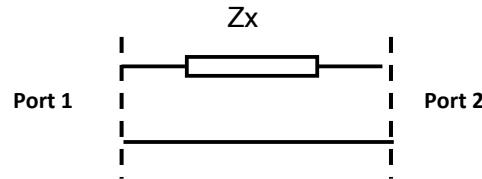
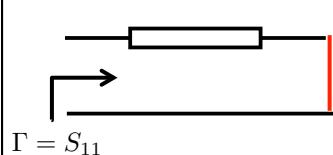


Conversion measurements of lumped elements



Reflection Measurements

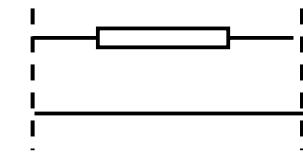


$$\Gamma = S_{11}$$

$$S_{11} = \frac{Z_x - Z_0}{Z_x + Z_0}$$

$$Z_x = Z_0 \frac{1 + S_{11}}{1 - S_{11}}$$

Transmission Measurements

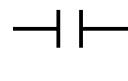


$$S_{12} = \frac{2Z_0}{Z_x + 2Z_0}$$

$$Z_x = Z_0 \frac{2(1 - S_{12})}{S_{12}}$$

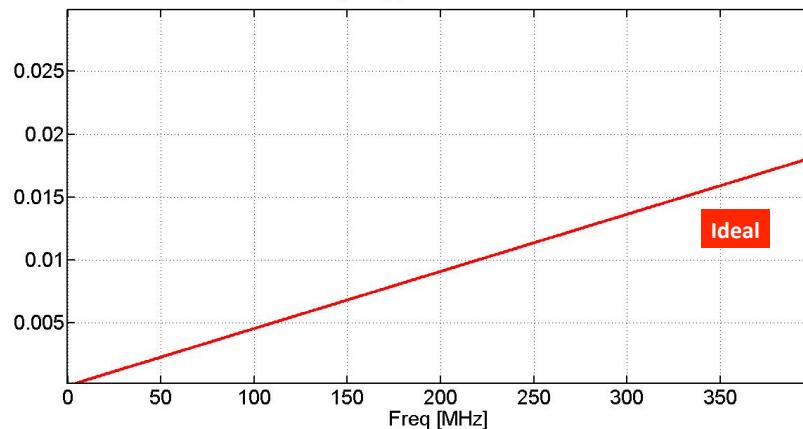
Formulas implemented in the modern Vector Network Analyzers

Example: capacitor

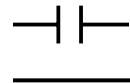


$$Y = j\omega C$$

Imaginary part of Y measured

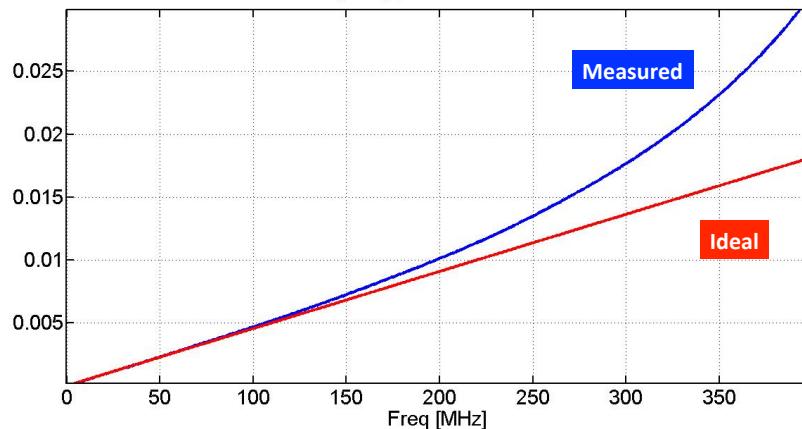


Example: capacitor



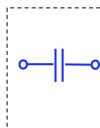
$$Y = j\omega C$$

Imaginary part of Y measured



Measuring lumped elements: sources of inaccuracy

- TRUE

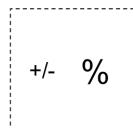


- EFFECTIVE



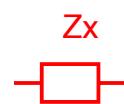
- INDICATED

+/- %



Instrument Test fixture Real world device

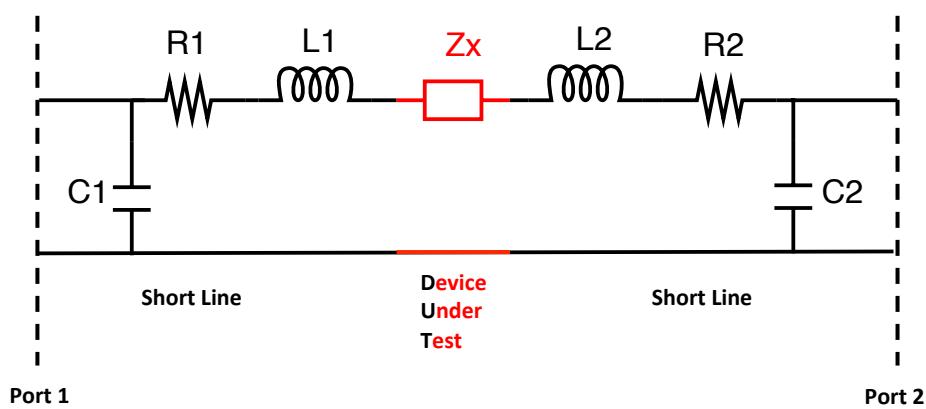
Measuring lumped elements at high frequency



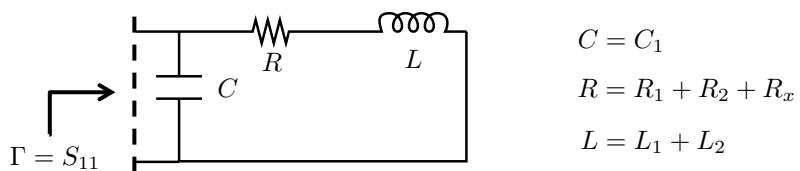
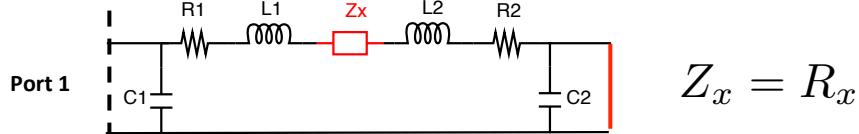
Device
Under
Test

Measuring lumped elements at high frequency

Effects of the connection to the measurement instrument



Example: Resistor at high frequency (reflection)



$$Y = j\omega C + \frac{1}{R + j\omega L} = \frac{R}{R^2 + (\omega L)^2} + j\omega \left[C - \frac{L}{R^2 + (\omega L)^2} \right]$$

$$Z = \frac{R}{(1 - \omega^2 LC)^2 + (\omega RC)^2} + j\omega \left[\frac{L - \omega^2 L^2 C - R^2 C}{(1 - \omega^2 LC)^2 + (\omega RC)^2} \right]$$

Real part of the impedance



$$Z = \frac{R}{(1 - \omega^2 LC)^2 + (\omega RC)^2} + j\omega \left[\frac{L - \omega^2 L^2 C - R^2 C}{(1 - \omega^2 LC)^2 + (\omega RC)^2} \right]$$

